

October 2013

## FDP2532 / FDB2532

## N-Channel PowerTrench<sup>®</sup> MOSFET 150 V, 79 A, 16 m $\Omega$

#### **Features**

- $R_{DS(on)}$  = 14  $m\Omega$  ( Typ.) @  $V_{GS}$  = 10 V,  $I_D$  = 33 A
- $Q_{G(tot)}$  = 82 nC ( Typ.) @  $V_{GS}$  = 10 V
- · Low Miller Charge
- Low Q<sub>rr</sub> Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)

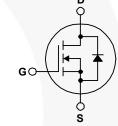
#### **Applications**

- · Consumer Appliances
- · Synchronous Rectification
- · Battery Protection Circuit
- · Motor drives and Uninterruptible Power Supplies
- · Micro Solar Inverter

Formerly developmental type 82884







MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

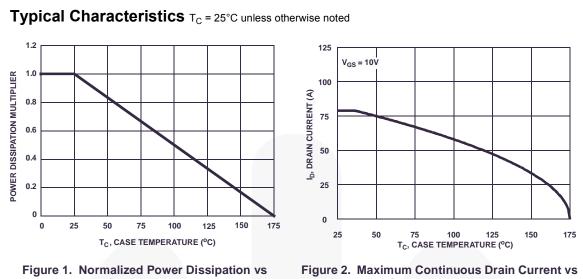
| Symbol            | Parameter   | FDP2532 / FDB2532 | Unit |
|-------------------|---|-------------------|------|
| V <sub>DSS</sub>  | Drain to Source Voltage   | 150               | V    |
| V <sub>GS</sub>   | Gate to Source Voltage  | ±20               | V    |
|                   | Drain Current   |                   |      |
| I <sub>D</sub>    | Continuous (T <sub>C</sub> = 25°C, V <sub>GS</sub> = 10V)                                 | 79                | Α    |
|                   | Continuous (T <sub>C</sub> = 100°C, V <sub>GS</sub> = 10V)                                | 56                | Α    |
|                   | Continuous ( $T_{amb} = 25^{\circ}C$ , $V_{GS} = 10V$ , $R_{\theta JA} = 43^{\circ}C/W$ ) | 8                 | Α    |
|                   | Pulsed  | Figure 4          | Α    |
| E <sub>AS</sub>   | Single Pulse Avalanche Energy (Note 1)  | 400               | mJ   |
| P <sub>D</sub>    | Power dissipation   | 310               | W    |
|                   | Derate above 25°C   | 2.07              | W/°C |
| $T_J$ , $T_{STG}$ | Operating and Storage Temperature   | -55 to 175        | °C   |

#### **Thermal Characteristics**

| $R_{\theta JC}$ | Thermal Resistance Junction to Case, Max. TO-220, D2-PAK                 | 0.61 | °C/W |
|-----------------|--|------|------|
| $R_{\theta JA}$ | Thermal Resistance Junction to Ambient, Max. TO-220, D2-PAK (Note 2)     | 62   | °C/W |
| $R_{\theta JA}$ | Thermal Resistance Junction to Ambient D²-PAK, Max. 1in² copper pad area | 43   | °C/W |

| Device Marking      |                               | Device                            | Package   | R  | eel Size   | Tape '   | Width  | Qua       | ntity |
|---------------------|-------------------------------|-----------------------------------|---|--|------------|----------|--|-----------|-------|
| FDB2532             |                               | FDB2532                           | D²-PAK 33   |  | 30 mm      | 24 mm    |  | 800 units |       |
| FDP2532 FDP2532     |                               | TO-220 Tube                       |   | N/A  |            | 50 units |  |           |       |
| Electric            | al Char                       | acteristics T <sub>C</sub> = 25°C | unless otherw   | ise not  | ed         |          |  |           |       |
| Symbol              | Parameter                     |                                   | Tes   | Test Conditions  |            | Min      | Тур  | Max       | Unit  |
| Off Chara           | cteristics                    | S                                 |   |  | •          |          | •  | •         | -     |
| B <sub>VDSS</sub>   | Drain to S                    | ource Breakdown Voltage           | I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V                    |  | 150        | -        | -  | V         |       |
|                     | 7 0-4-                        |                                   |   | V <sub>DS</sub> = 120V                                       |            | -        | -  | 1         | _     |
| I <sub>DSS</sub>    | Zero Gate                     | e Voltage Drain Current           | $V_{GS} = 0V$   | $_{\rm S}$ = 0V $T_{\rm C}$ = 150°C                          |            | -        | -  | 250       | μΑ    |
| I <sub>GSS</sub>    | Gate to So                    | ource Leakage Current             | V <sub>GS</sub> = ±20   |  |            | -        | -  | ±100      | nA    |
| On Chara            | cteristics                    | 6                                 |   |  |            |          |  |           |       |
| V <sub>GS(TH)</sub> | Gate to Se                    | ource Threshold Voltage           | V <sub>GS</sub> = V <sub>DS</sub>                               | s, I <sub>D</sub> = 2  | 250μΑ      | 2        | -  | 4         | V     |
| 33(11.)             |                               |                                   | I <sub>D</sub> = 33A, \   |  |            | -        | 0.014  | 0.016     |       |
|                     | Drain to Source On Resistance |                                   |   | $I_D = 16A, V_{GS} = 6V,$                                    |            |          | 0.016  | 0.024     | Ω     |
| r <sub>DS(ON)</sub> |                               |                                   | $I_D = 33A, V_{GS} = 10V,$<br>$T_C = 175^{\circ}C$              |  | -          | 0.040    | 0.048  |           |       |
| Dynamic             | Characte                      | eristics                          |   |  |            |          | •  |           |       |
| C <sub>ISS</sub>    | Input Cap                     | acitance                          | \   |  |            | - \      | 5870   | -         | pF    |
| C <sub>OSS</sub>    | Output Capacitance            |                                   |   | V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V,<br>f = 1MHz     |            | -        | 615  | -         | pF    |
| C <sub>RSS</sub>    | Reverse T                     | ransfer Capacitance               | 1 111112  | 1 - 11/11/12   |            | -        | 135  | -         | pF    |
| Q <sub>g(TOT)</sub> | Total Gate                    | e Charge at 10V                   | $V_{GS} = 0V$   |  |            | -        | 82   | 107       | nC    |
| Q <sub>g(TH)</sub>  | Threshold                     | Gate Charge                       | $V_{GS} = 0V$   | $V_{GS}$ = 0V to 2V $V_{DD}$ = 75V $I_D$ = 33A $I_g$ = 1.0mA |            | -        | 11   | 14        | nC    |
| Q <sub>gs</sub>     | Gate to So                    | ource Gate Charge                 |   |  |            | -        | 23   | -         | nC    |
| Q <sub>gs2</sub>    | Gate Cha                      | rge Threshold to Plateau          |   |  |            | -        | 13   | -         | nC    |
| Q <sub>gd</sub>     | Gate to D                     | rain "Miller" Charge              |   |  |            | -        | 19   | -         | nC    |
| Resistive           | Switchin                      | ng Characteristics (V             | <sub>GS</sub> = 10V)  |  |            |          |  |           |       |
| t <sub>ON</sub>     | Turn-On T                     | ime                               |   |  |            | -/       | -  | 69        | ns    |
| t <sub>d(ON)</sub>  | Turn-On E                     | Delay Time                        |   |  |            | -/-      | 16   | - /       | ns    |
| t <sub>r</sub>      | Rise Time                     | )                                 | $V_{DD} = 75V, I_D = 33A$<br>$V_{GS} = 10V, R_{GS} = 3.6\Omega$ |  | -          | 30       | -/   | ns        |       |
| t <sub>d(OFF)</sub> | Turn-Off D                    | Delay Time                        |   |  | -          | 39       | - /-   | ns        |       |
| t <sub>f</sub>      | Fall Time                     |                                   |   |  | -          | 17       | / -  | ns        |       |
| t <sub>OFF</sub>    | Turn-Off T                    | ime                               |   |  |            | -        | -  | 84        | ns    |
| Orain-Sou           | ırce Dioc                     | le Characteristics                |   |  |            |          |  |           |       |
| \ /                 |                               |                                   | I <sub>SD</sub> = 33A   |  | - ,        | -        | 1.25   | V         |       |
| $V_{SD}$            |                               |                                   | I <sub>SD</sub> = 16A   |  |            | -        | -  | 1.0       | V     |
|                     |                               |                                   | $I_{SD} = 33A$ , $dI_{SD}/dt = 100A/\mu s$                      |  |            |          | <del>                                     </del> |           |       |
| t <sub>rr</sub>     | Reverse F                     | Recovery Time                     | $I_{SD} = 33A$  | dl <sub>SD</sub> /d  | t= 100A/μs | -        | -  | 105       | ns    |

Notes: 1: Starting  $T_J$  = 25°C, L = 0.5 mH,  $I_{AS}$  = 40A. 2: Pulse Width = 100s



**Ambient Temperature** 

**Case Temperature** 

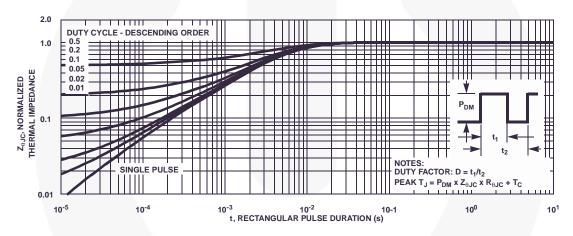


Figure 3. Normalized Maximum Transient Thermal Impedance

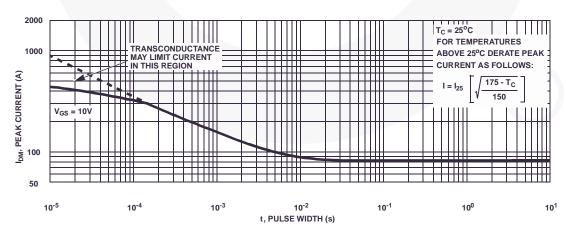


Figure 4. Peak Current Capability

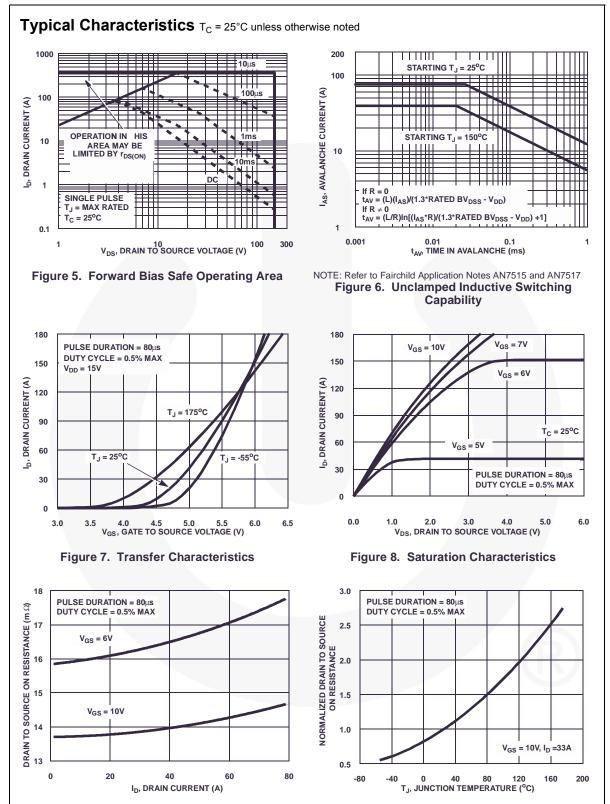


Figure 9. Drain to Source On Resistance vs Drain

Current

Figure 10. Normalized Drain to Source On

Resistance vs Junction Temperature

# Typical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted 1.4 $V_{GS} = V_{DS}, I_D = 250 \mu A$ 1.2 $V_{GS} = V_{DS}, I_D = 250 \mu A$ 1.2 $V_{GS} = V_{DS}, I_D = 250 \mu A$

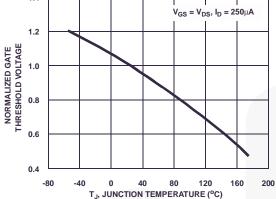
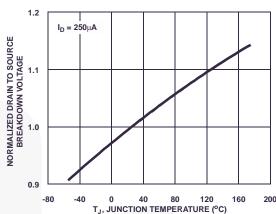


Figure 11. Normalized Gate Threshold Voltage vs
Junction Temperature

Figure 12. Normalized Drain to Source
Breakdown Voltage vs Junction Temperature



10000  $C_{OSS} = C_{DS} + C_{GD}$   $C_{RSS} = C_{GS} + C_{GD}$   $C_{RSS} = C_{GD}$ 1000  $V_{GS} = 0V, f = 1MHz$   $V_{DS}, DRAIN TO SOURCE VOLTAGE (V)$ 

Figure 13. Capacitance vs Drain to Source Voltage

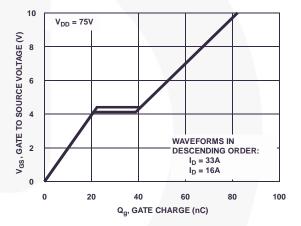


Figure 14. Gate Charge Waveforms for Constant Gate Currents

## **Test Circuits and Waveforms**

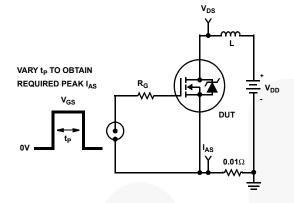


Figure 15. Unclamped Energy Test Circuit

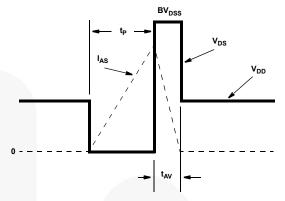


Figure 16. Unclamped Energy Waveforms

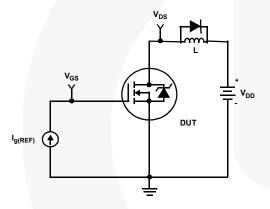


Figure 17. Gate Charge Test Circuit

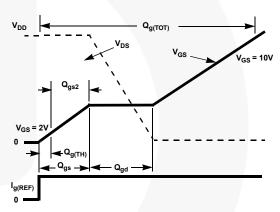


Figure 18. Gate Charge Waveforms

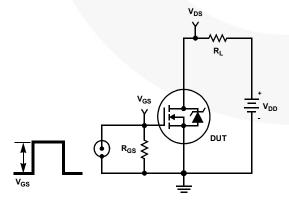


Figure 19. Switching Time Test Circuit

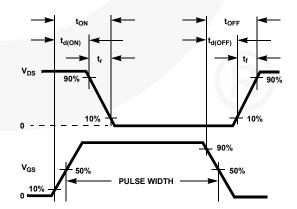


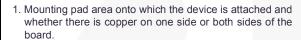
Figure 20. Switching Time Waveforms

#### Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature,  $T_{JM}$ , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation,  $P_{DM}$ , in an application. Therefore the application's ambient temperature,  $T_A$  (°C), and thermal resistance  $R_{\theta JA}$  (°C/W) must be reviewed to ensure that  $T_{JM}$  is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \tag{EQ. 1}$$

In using surface mount devices such as the TO-263 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of  $\mathsf{P}_{\mathsf{DM}}$  is complex and influenced by many factors:



- The number of copper layers and the thickness of the hoard
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the  $R_{\theta JA}$  for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 26.51 + \frac{19.84}{(0.262 + Area)}$$
 (EQ. 2)

Area in Inches Squared

$$R_{\theta JA} = 26.51 + \frac{128}{(1.69 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

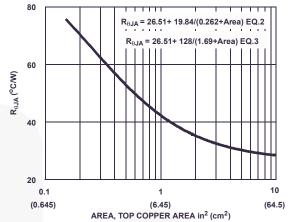
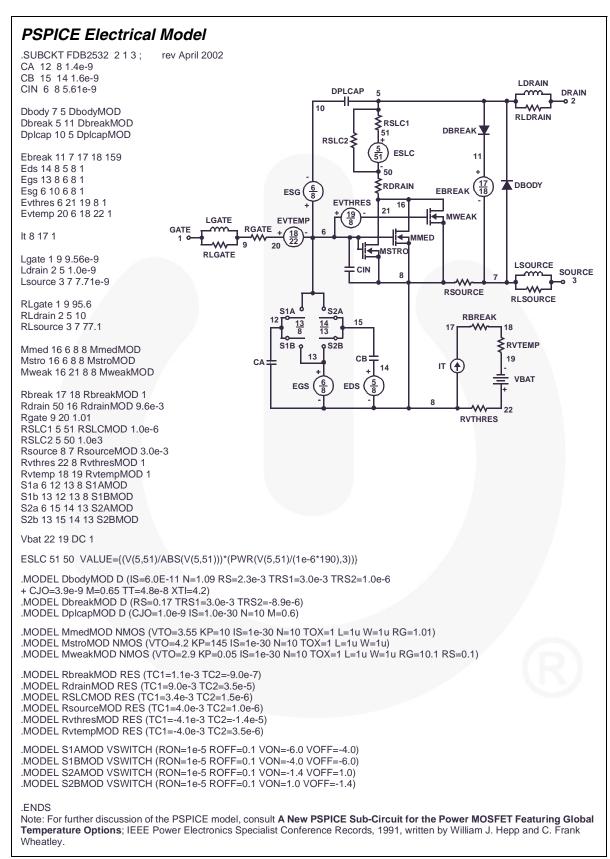


Figure 21. Thermal Resistance vs Mounting
Pad Area



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#### SABER Electrical Model REV April 2002 ttemplate FDB2532 n2.n1.n3 electrical n2,n1,n3 dp..model dbodymod = (isl=6.0e-11,nl=1.09,rs=2.3e-3,trs1=3.0e-3,trs2=1.0e-6,cjo=3.9e-9,m=0.65,tt=4.8e-8,xti=4.2) dp..model dbreakmod = (rs=0.17,trs1=3.0e-3,trs2=-8.9e-6) dp..model dplcapmod = (cjo=1.0e-9,isl=10.0e-30,nl=10,m=0.6) m..model mmedmod = $(type=_n, vto=3.55, kp=10, is=1e-30, tox=1)$ m..model mstrongmod = $(type=_n, vto=4.2, kp=145, is=1e-30, tox=1)$ m..model mweakmod = (type=\_n,vto=2.9,kp=0.05,is=1e-30, tox=1,rs=0.1) LDRAIN sw\_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-6.0,voff=-4.0) DPI CAP DRAIN sw\_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-4.0,voff=-6.0) sw\_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-1.4,voff=1.0) RLDRAIN sw\_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=1.0,voff=-1.4) ₹RSLC1 c.ca n12 n8 = 1.4e-951 RSLC2 ₹ c.cb n15 n14 = 1.6e-9ISCL c.cin n6 n8 = 5.61e-9DBREAK Y 50 dp.dbody n7 n5 = model=dbodymod **≷**RDRAIN dp.dbreak n5 n11 = model=dbreakmod 8 ESG DBODY dp.dplcap n10 n5 = model=dplcapmod **EVTHRES** (19 8 spe.ebreak n11 n7 n17 n18 = 159 <sub>GATE</sub> **LGATE EVTEMP** RGATE spe.eds n14 n8 n5 n8 = 1 (18 22 **EBREAK** MMED 9 20 spe.egs n13 n8 n6 n8 = 1 **RLGATE** spe.esg n6 n10 n6 n8 = 1 **LSOURCE** spe.evthres n6 n21 n19 n8 = 1 CIN SOURCE spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RI SOURCE i.it n8 n17 = 1RBREAK 14 13 I.lgate n1 n9 = 9.56e-917 18 I.ldrain n2 n5 = 1.0e-9**₹**RVTEMP I.Isource n3 n7 = 7.71e-919 СВ CA IT (♠ res.rlgate n1 n9 = 95.6 VBAT res.rldrain n2 n5 = 10 EGS res.rlsource n3 n7 = 77.1 m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u **RVTHRES** m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u res.rbreak n17 n18 = 1, tc1=1.1e-3,tc2=-9.0e-7 res.rdrain n50 n16 = 9.6e-3, tc1=9.0e-3,tc2=3.5e-5 res.rgate n9 n20 = 1.01 res.rslc1 n5 n51 = 1.0e-6, tc1=3.4e-3,tc2=1.5e-6 res.rslc2 n5 n50 = 1.0e3 res.rsource n8 n7 = 3.0e-3, tc1=4.0e-3,tc2=1.0e-6 res.rvthres n22 n8 = 1, tc1=-4.1e-3,tc2=-1.4e-5res.rvtemp n18 n19 = 1, tc1=-4.0e-3, tc2=3.5e-6sw vcsp.s1a n6 n12 n13 n8 = model=s1amod sw\_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw\_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw\_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { i (n51->n50) +=iscl iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))\*((abs(v(n5,n51)\*1e6/190))\*\*3))

#### SPICE Thermal Model JUNCTION th REV 26 February 2002 FDB2532 CTHERM1 TH 6 7.5e-3 CTHERM2 6 5 8.0e-3 CTHERM3 5 4 9.0e-3 RTHERM1 CTHERM1 CTHERM4 4 3 2.4e-2 CTHERM5 3 2 3.4e-2 CTHERM6 2 TL 6.5e-2 6 RTHERM1 TH 6 3.1e-4 RTHERM2 6 5 2.5e-3 RTHERM3 5 4 2.0e-2 RTHERM2 CTHERM2 RTHERM4 4 3 8.0e-2 RTHERM5 3 2 1.2e-1 RTHERM6 2 TL 1.3e-1 SABER Thermal Model SABER thermal model FDB2532 RTHERM3 CTHERM3 template thermal\_model th tl thermal\_c th, tl ctherm.ctherm1 th 6 =7.5e-3 ctherm.ctherm2 6 5 =8.0e-3 ctherm.ctherm3 5 4 = 9.0e-3 ctherm.ctherm4 4 3 = 2.4e-2 ctherm.ctherm5 3 2 =3.4e-2 RTHERM4 CTHERM4 ctherm.ctherm6 2 tl =6.5e-2 rrtherm.rtherm1 th 6 = 3.1e-4 rtherm.rtherm2 6 5 = 2.5e-3 3 rtherm.rtherm3 5 4 = 2.0e-2 rtherm.rtherm4 4 3 =8.0e-2 rtherm.rtherm5 3 2 =1.2e-1 RTHFRM5 CTHERM5 rtherm.rtherm6 2 tl =1.3e-1 RTHERM6 CTHERM6 CASE

#### **Mechanical Dimensions**

## TO-220 3L

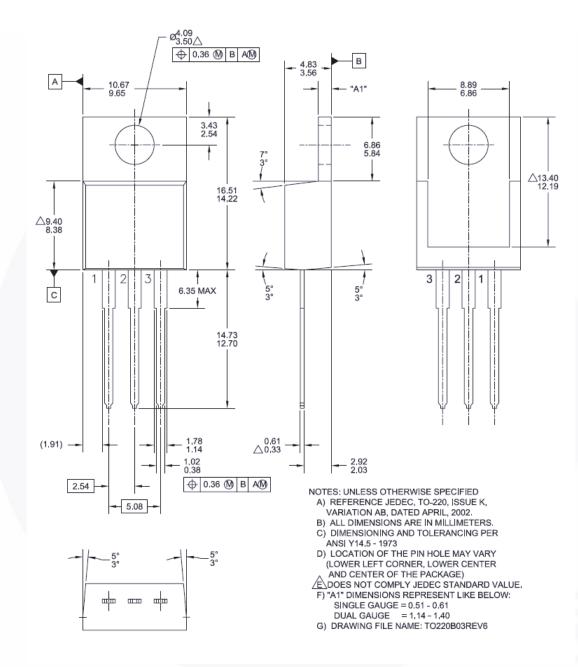


Figure 22. TO-220, Molded, 3Lead, Jedec Variation AB

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Dimension in Millimeters

#### **Mechanical Dimensions**

## TO-263 2L (D<sup>2</sup>PAK)

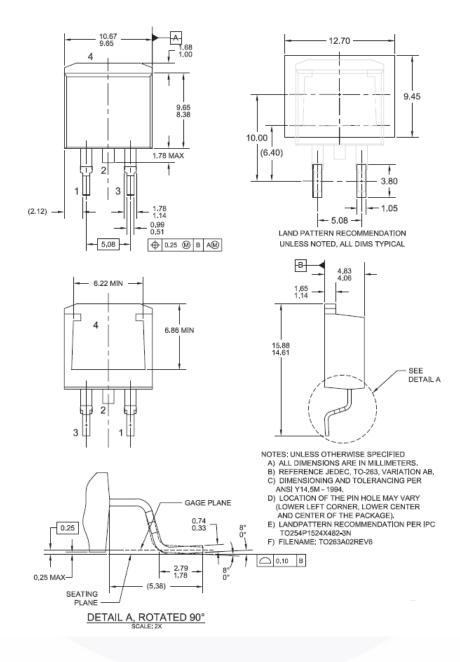


Figure 23. 2LD, TO263, Surface Mount

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Dimension in Millimeters





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|--------------------------|-----------------------|---|
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| Preliminary              | First Production      | Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design. |
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